- **Low-Output Skew for Clock-Distribution and Clock-Generation Applications**
- **Differential Low-Voltage Pseudo ECL (LVPECL)-Compatible Inputs and Outputs**
- **Distributes Differential Clock Inputs to Nine Differential Clock Outputs**
- **Output Reference Voltage (V_{REF}) Allows Distribution From a Single-Ended Clock Input**
- **LVTTL-Compatible Output Enable**
- **Packaged in Plastic Chip Carrier**
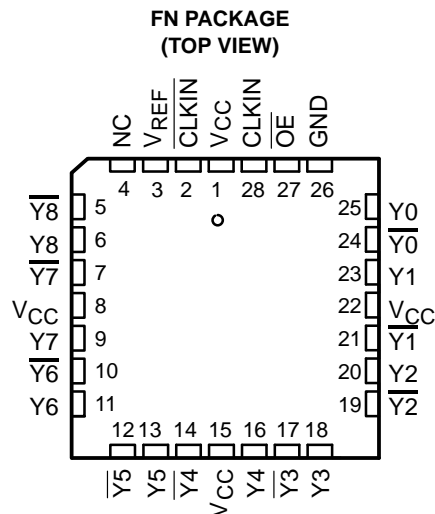
FN PACKAGE
(TOP VIEW)

NC – No internal connection

description

This differential LVPECL clock-driver circuit distributes one pair of differential LVPECL clock inputs (CLKIN, $\overline{CLKIN}$) to nine pairs of differential clock (Y, $\overline{Y}$) outputs with minimum skew for clock distribution. It is specifically designed for driving 50-Ω transmission lines.

When the output-enable ($\overline{OE}$) is low, the nine differential outputs switch at the same frequency as the differential clock inputs. When $\overline{OE}$ is high, the nine differential outputs are in static states (Y outputs are in the low state, $\overline{Y}$ outputs are in the high state).

The V_{REF} output can be strapped to the $\overline{CLKIN}$ input for a single-ended CLKIN input.

The CDC112 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

INPUTS			OUTPUTS	
CLKIN	$\overline{CLKIN}$	$\overline{OE}$	Yn	$\overline{Y}n$
X	X	H	L	H
L	H	L	L	H
H	L	L	H	L
L	V_{REF}	L	L	H
H	V_{REF}	L	H	L
V_{REF}	L	L	H	L
V_{REF}	H	L	L	H

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logic diagram

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} .... −0.5 V to 4.6 V
Input voltage range, V_I (see Note 1) .... −0.5 V to V_{CC} + 0.5 V
Output voltage range, V_O (see Note 1) .... −0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$) .... −18 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) .... −18 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) .... −50 mA
Continuous current through V_{CC} or GND .... ± 80 mA
Maximum power dissipation at T_A = 55°C (in still air) .... 525 mW
Storage temperature range, T_{stg} .... −65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTE 1:   The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

TEXAS INSTRUMENTS

recommended operating conditions

			MIN	MAX	UNIT
V_{CC}	Supply voltage		3	3.6	V
V_{IH}	High-level input voltage (CLKIN, $\overline{CLKIN}$ only)	V_{CC} = 3 V to 3.6 V	$V_{CC}-1.165$	$V_{CC}-0.88$	V
		V_{CC} = 3.3 V	2.135	2.42	
V_{IL}	Low-level input voltage (CLKIN, $\overline{CLKIN}$ only)	V_{CC} = 3 V to 3.6 V	$V_{CC}-1.81$	$V_{CC}-1.475$	V
		V_{CC} = 3.3 V	1.49	1.825	
V_{IH}	High-level input voltage ($\overline{OE}$ only)		2		V
V_{IL}	Low-level input voltage ($\overline{OE}$ only)			0.8	V
f_{clock}	Input clock frequency			500	MHz
T_A	Operating free-air temperature		0	70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	MAX	UNIT
V_{REF}	V_{CC} = 3 V to 3.6 V		$V_{CC}-1.38$	$V_{CC}-1.26$	V
	V_{CC} = 3.3 V		1.925	2.075	
V_{OH}	V_{CC} = 3 V to 3.6 V		$V_{CC}-1.025$	$V_{CC}-0.88$	V
	V_{CC} = 3.3 V		2.275	2.42	
V_{OL}	V_{CC} = 3 V to 3.6 V		$V_{CC}-1.81$	$V_{CC}-1.62$	V
	V_{CC} = 3.3 V		1.49	1.68	
I_I	V_I = 2.4 V,	V_{CC} = 3 .6 V		150	µA
I_{CC}	I_O = 0,	V_{CC} = 3 .6 V		80	mA

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (see Figures 1 and 2)

| PARAMETER	FROM (INPUT)	TO (OUTPUT)	$T_A = 0°C$		$T_A = 25°C$		$T_A = 70°C$		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	CLKIN, $\overline{CLKIN}$	Y, $\overline{Y}$	475	625	480	630	485	635	ps
t_{PHL}			475	625	480	630	485	635	
t_{PHL}	$\overline{OE}$	Y, $\overline{Y}$		900		900		900	ps
$t_{sk(o)}$		Y, $\overline{Y}$		50		50		50	ps
$t_{sk(pr)}$		Y, $\overline{Y}$		150		150		150	ps
t_r		Y, $\overline{Y}$	200	600	200	600	200	600	ps
t_f		Y, $\overline{Y}$	200	600	200	600	200	600	ps

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CDC112
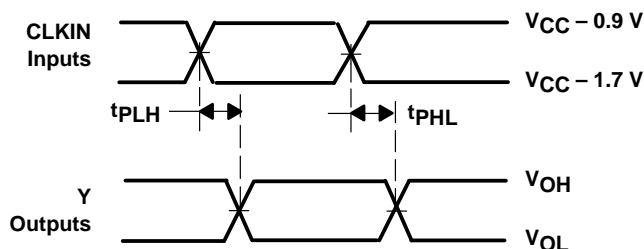## 1-LINE TO 9-LINE DIFFERENTIAL LVPECL CLOCK DRIVER

SCAS322D – DECEMBER 1993 – REVISED APRIL 1996

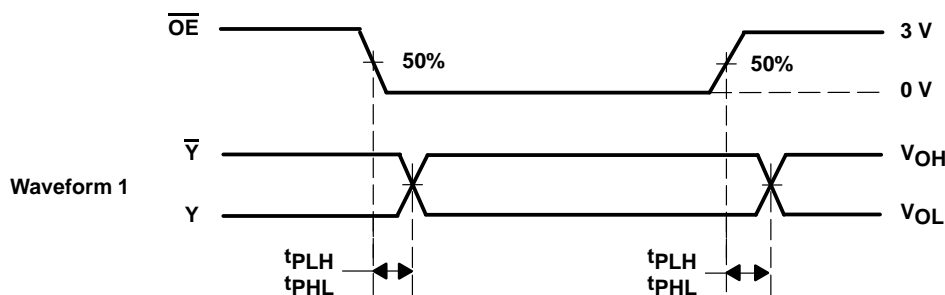## PARAMETER MEASUREMENT INFORMATION
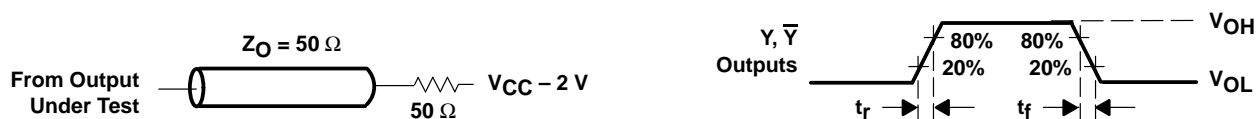
LOAD CIRCUIT FOR OUTPUTS

**VOLTAGE WAVEFORMS
RISE AND FALL TIMES**

**VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES**

Waveform 1

**VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES**

NOTES: A. All input pulses are supplied by generators having the following characteristics: PRR ≤ 45 MHz, Z_O = 50 Ω, t_r ≤ 1 ns, t_f ≤ 1 ns.
B. Waveform 1 is for a $\overline{Y}$ output with internal conditions such that the output is high except when disabled, and for a Y output with internal conditions such that the output is low except when disabled.
C. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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PARAMETER MEASUREMENT INFORMATION

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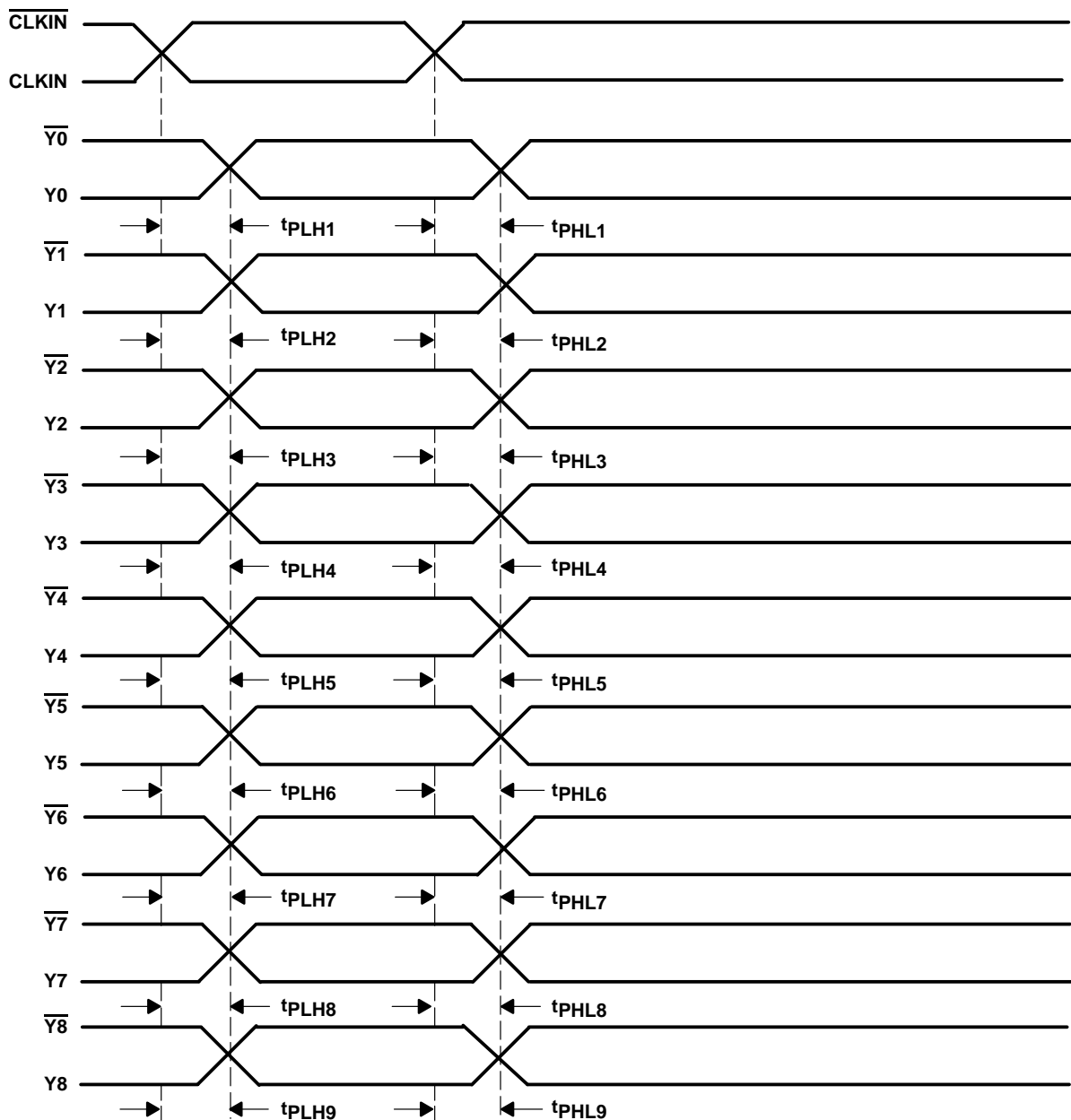
NOTES: A. Output skew, $t_{sk(o)}$, is calculated as the greater of:
  – The difference between the fastest and slowest t_{PLHn} (n = 1, 2, . . . 9)
  – The difference between the fastest and slowest t_{PHLn} (n = 1, 2, . . . 9)
  B. Process skew, $t_{sk(pr)}$, is calculated as as the greater of:
  – The difference between the fastest and slowest t_{PLHn} (n = 1, 2, . . . 9)
  – The difference between the fastest and slowest t_{PHLn} (n = 1, 2, . . . 9) across multiple devices

Figure 2. Waveforms for Calculation of $t_{sk(o)}$, $t_{sk(pr)}$

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